

Module Encapsulation Materials, Processing and Testing

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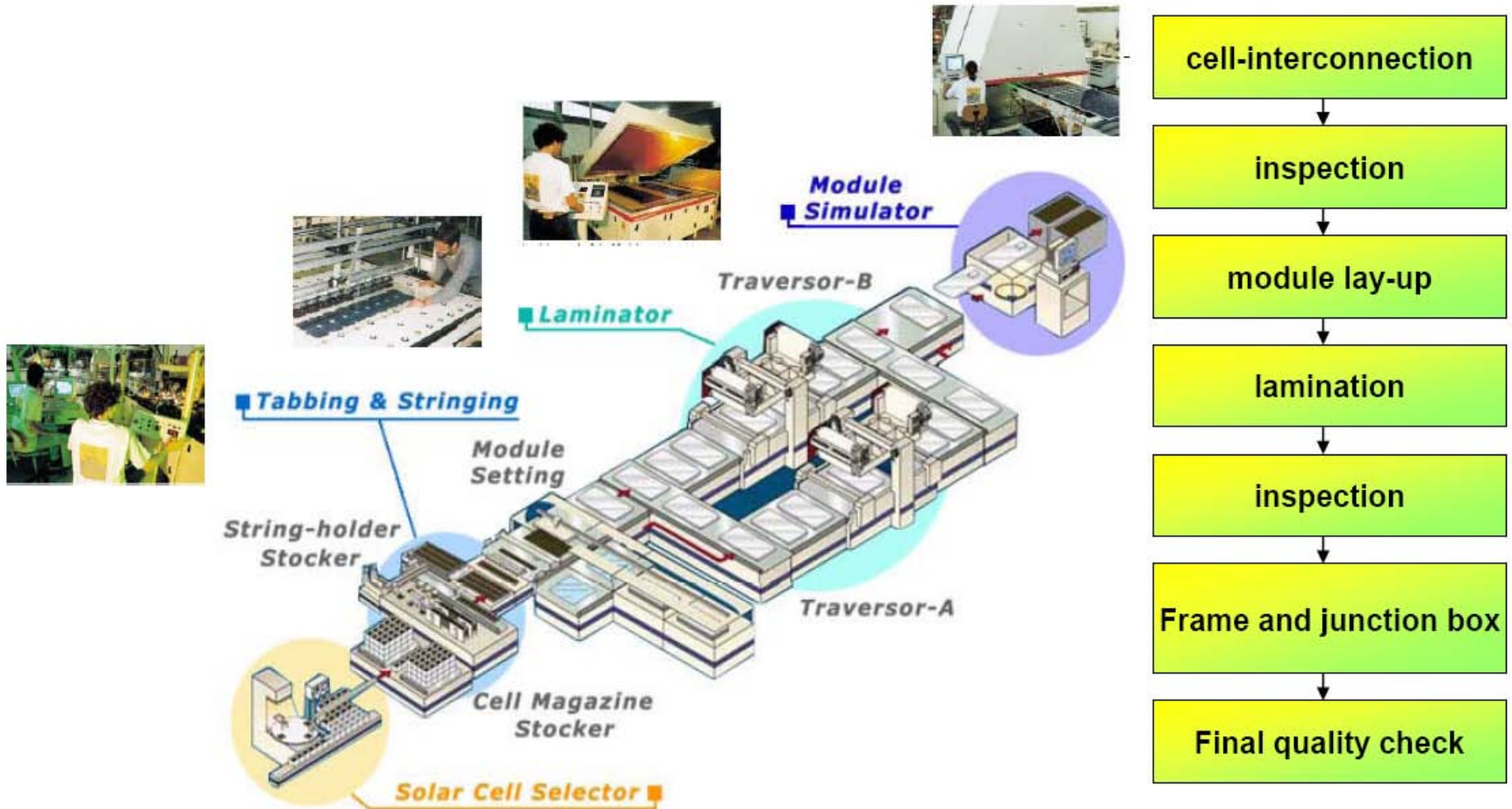
NREL/PR-520-44666

**APP International PV Reliability Workshop
Dec. 4-5, 2008, SJTU, Shanghai, China**

Outline

- **Encapsulation Components (Commercial Products)**
 - Superstrates: Glass or Tefzel/Tedlar
 - Encapsulants (EVA and Non-EVA - TPU, PVB, ... etc.)
 - Substrates: Back Foils (or Backsheets) or Glass
 - Edge Seals
 - Materials Properties
- **Processing**
 - Typical module constructions
 - Module Lamination – Curing Process
- **Materials-Level Testing**
 - Optical, Electrical, Mechanical
 - Photothermal and damp heat tests
- **Field-Degraded Modules (Photos)**
 - Effects of materials and encapsulation quality
- **Conclusions**

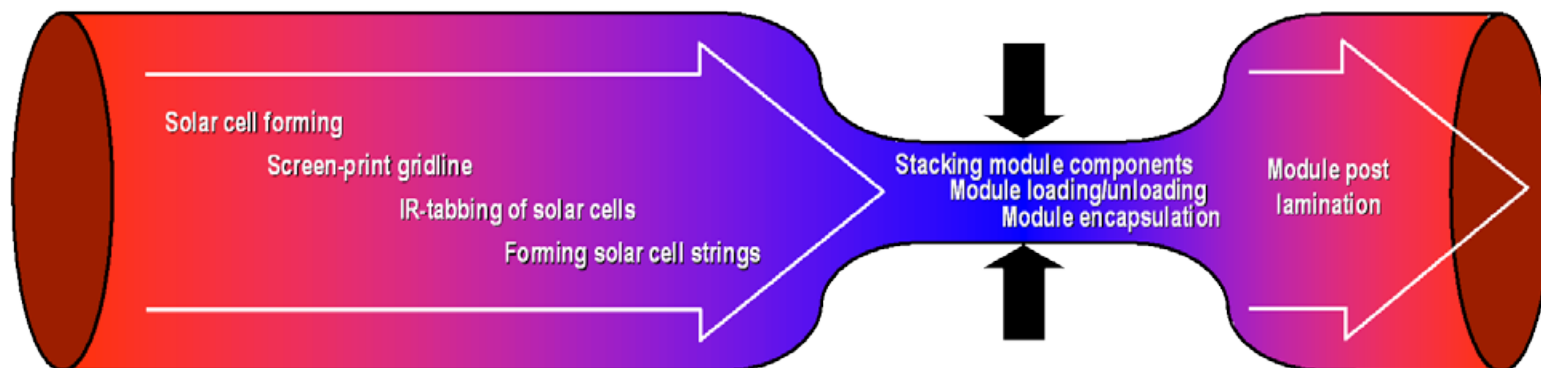
PV Module Production Line



Viewgraph showing the module production schematically

Encapsulation:

Manufacturing Bottleneck in (c-Si) PV Module Fabrication Process

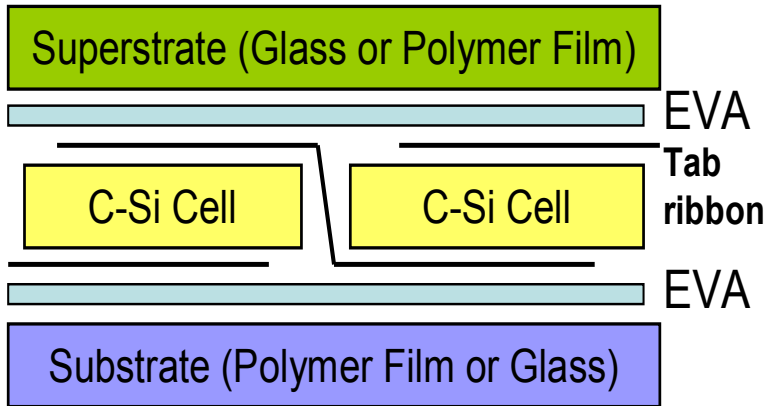


Importance of PV Module Packaging --

- High module reliability for 20-30 year service life
- “Packaging is the predominant cause of failure in modules” – remark of a DOE SETP PV Program reviewer, 2006

Typical PV Module Encapsulation Configurations

I. Crystalline Si-based Module



Common feature:

Glass/EVA/c-Si Cells/EVA/backfoil

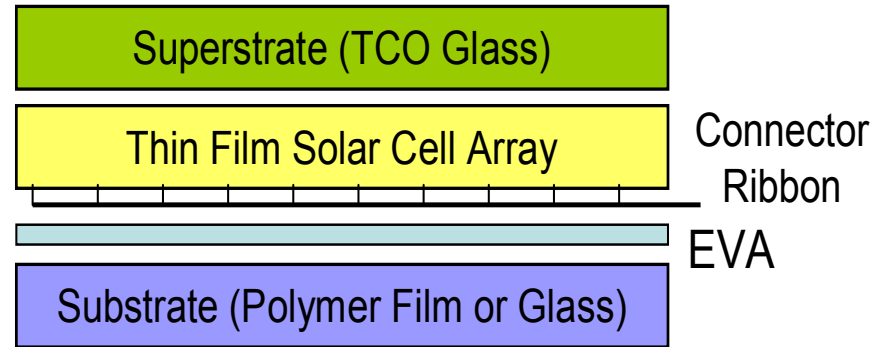
Backfoil selection:

TPT: Tedlar/PET/Tedlar

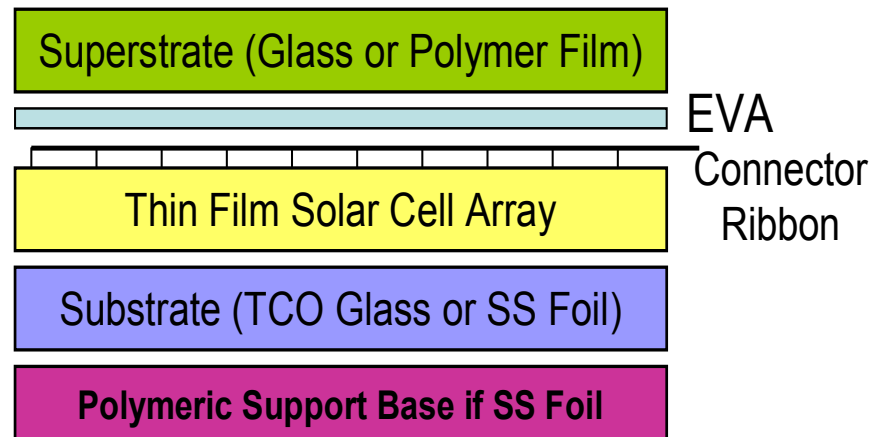
TPE: Tedlar/PET/EVA

PET: Polyester

II. Superstrate-Deposited Thin Film Module



III. Substrate-Deposited Thin Film Module



Elements for Making Good Encapsulation of (c-Si) PV Modules

- **Good (right) glass super-/substrate**
- **High-performance encapsulant**
- **Good (right) backfoil or substrate**
- **Good (correct) lamination process with proper handling of stack and temperature-pressure-time (T-P-t) profile**
- **Good edge seal if the design needs**

Module Encapsulation Materials - 1

- **Polymeric Encapsulants (Pottants):**
Most critical element in module encapsulation and reliability
 - EVA (most commonly used and cheapest; the only field-proven over 20 years)
 - Non-EVA
 - TPU
 - PVB
 - Silicones
 - Silicone/PU hybrid
 - Ionomer
 - Other new polymers
 - UV-Curable Resin
- **Edge Sealants** (for Al-framed c-Si or thin-film modules)
 - Polybutyl
 - Silicones
 - Desiccant-type
 - PIB-type

Module Encapsulation Materials - 2

Superstrate:

- **Glass**
 - Low-Iron
 - Tempered
 - Plain or Textured
 - UV filtering (Ce-glass)
 - SiO₂ AR Coatings
- **Fluoropolymer**
 - Tefzel
 - Tedlar
 - THV220
(to replace EVA/Tefzel)

Substrate:

- **Polymer Multi-laminates (Backsheet; Backfoil)**
 - **Tedlar-based:**
 - TPT: Tedlar/PET/Tedlar
 - TPE: Tedlar/PET/EVA
 - TAT: Tedlar/Al foil/EVA
 - TPAT: Tedlar/PET/Al foil/Tedlar
 - TPOT: Tedlar/PET/Oxide/Tedlar
 - PAP: PEN/Al foil/PET
 - **PET or PEN-based** (to replace expensive Tedlar)
 - Protekt
 - Teijin Teonex
 - BaSO₄-filled PET
- **Glass**

Primary Functions and Requirements of Encapsulant

Functions:

- **Optical coupling** – refractive index (n) matching
- **Electrical Insulation** – dielectric strength and volume resistivity
- **Mechanical support** – fixation of cells and adhesion strength
- **Physical insulation** – separate cells & cell strings
- **Physical protection** – from weathering-induced and environmental damages
- **Thermal conduction**

Requirements:

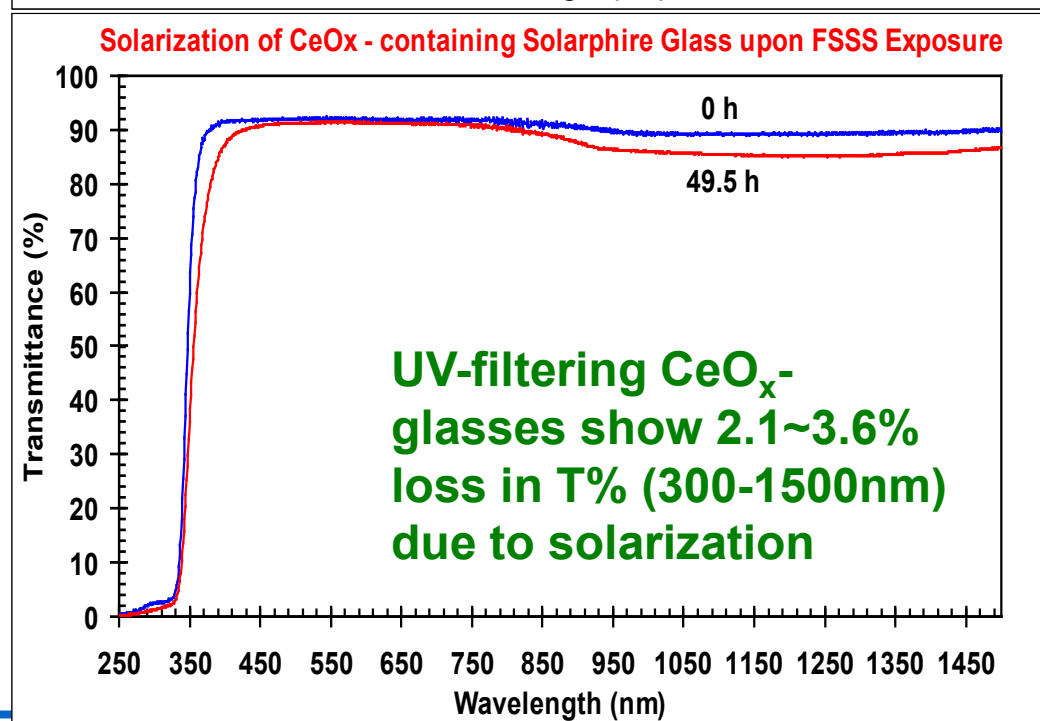
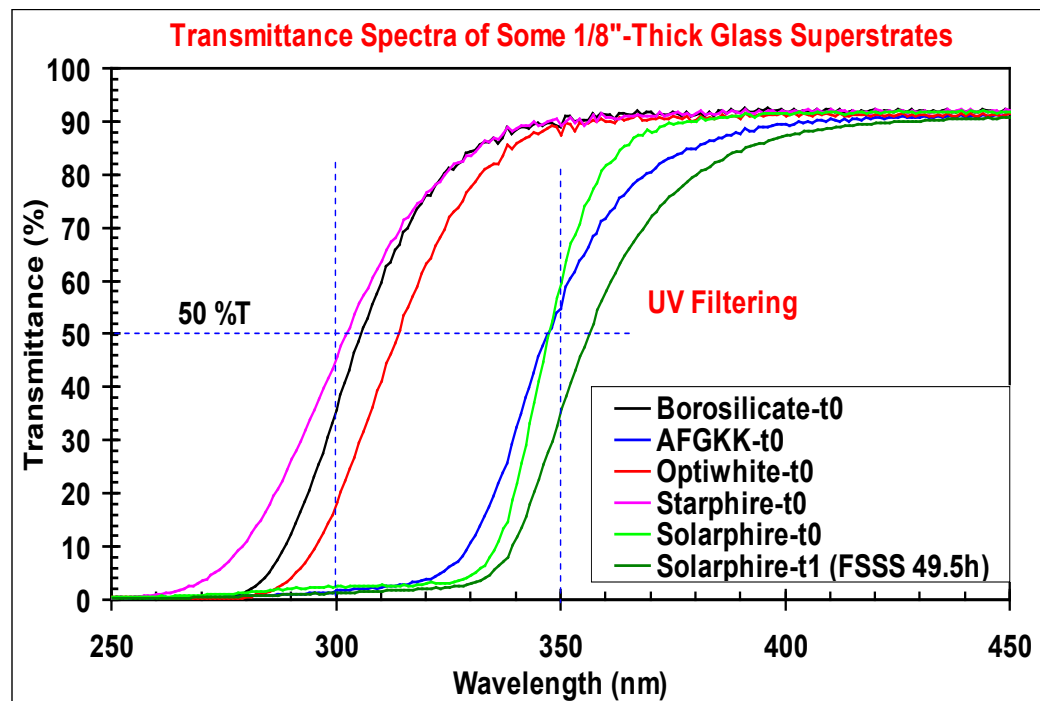
- High T%
- Matching R.I. (n)
- High dielectric breakdown
- High volume resistivity
- High adhesion strength
- Mechanically strong, resistant to break or tear
- Low moisture absorption
- High resistance to UV-induced yellow-browning
- High resistance to UV and moisture-induced delamination

Select Encapsulant

- **Based on Module Design and Construction**
- **Cost Consideration**
- **Processing Equipment, Method, Conditions**
- **Materials: EVA, PVB, TPU, Silicone, Ionomer, UV-curable resin,...**
- **Tests:**
 - **Film transmission before and after processing or testing**
 - UV & Heat - induced yellowing (photothermal stability)
 - damp heat and thermal cycle – induced yellowing
 - **Proper processing conditions (T-P-t profile) with your laminator**
 - Curing degree & gel% (EVA)
 - **Adhesion strength** (e.g., 90° or 180° peel, or lap-shear test)
 - Initial (e.g., EVA to glass, Tedlar, or PET)
 - thermal cycle
 - humidity freeze
 - damp heat
 - **Electrical insulation** (e.g., volume resistivity, breakdown V)
 - **Mechanical strength** (tensile)

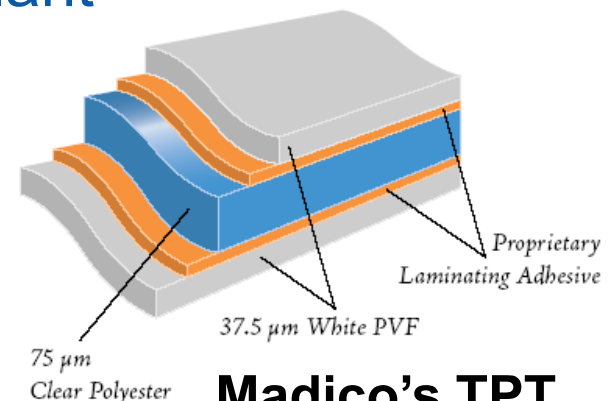
Select Glass Superstrate

- Low-Iron
- Tempered (c-Si PV)
- Type:
 - Plain or Textured
 - UV-transmitting
 - CeO_x UV-Filtering
 - SiO_2 AR Coating
- Test T% and degree of solarization
- Affect photo-(UV) stability of encapsulant
- Correctly use the non-float (non-tinned) side
- Cleaning - affects adhesion (delamination)



Select Backfoil (Backsheet)

- **Type (more commonly used) –**
 - **TPT-primed:** Tedlar/PET/Tedlar
 - TPE: Tedlar/PET/EVA (low VA%)
 - PET-based (polyester, primed or corona-treated)
 - PEN-based
- **Cost consideration**
- **Tests –**
 - adhesion strength with encapsulant
 - electrical insulation
 - mechanical strength
 - moisture-blocking (WVTR)
 - weathering durability



Madico's TPT

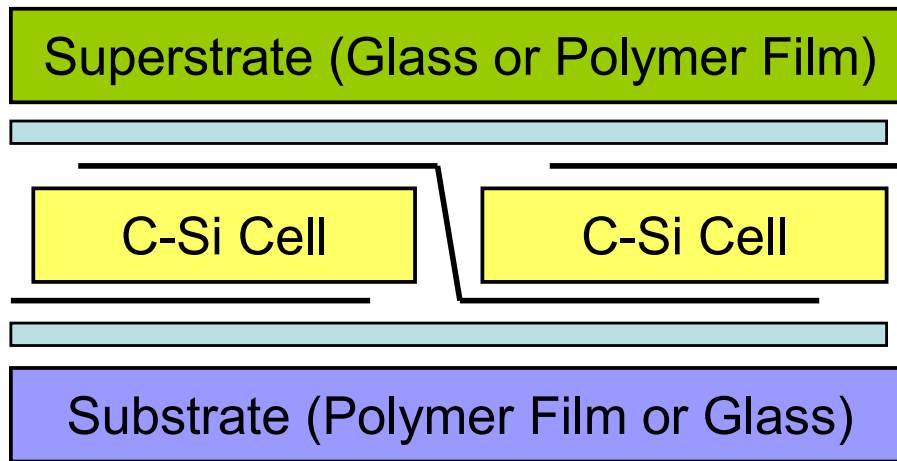
Select Edge Sealant

- **Primary function: to block moisture/water ingress**
- **Use depends on module design/construction**
- **Al-framed c-Si modules:**
 - Polybutyl (“hot butyl”)
 - Silicones (needs to know moisture-blocking property)
 - PIB-type (maybe the best)
 - Others (“U”-shaped rubber tapes)
- **Thin-Film CdTe and CIGS (glass/glass):**
 - Desiccant-type tapes (mechanical and adhesion strength may be weak)
- **Conduct immersion/hot-pot leaking tests**

An Example showing Various Tests Conducted to Determine Materials Properties and Processing

Material	T%	Gel	Volume Resistivity		Adhesion Strength	Water Vapor Transmission Rate		
	(400-1000 nm)	(%)	(ohm-cm)	(ohm-cm)	(N/mm) (90° Peel)	T (°C)	RH (%)	(g/m ² -day)
Tefzel (1.5 mil)	~94					20	85	1.80
Tefzel(1.5 mil)/EVA cured						38	82	6.55
Tefzel (5 mil)	87-92		7.60E+16					
	Cured Film	Fast-Cured	Uncured	Cured	To Plain KK glass			
China EVA-1	91 ± 1	95	(deep texture)	2.3~5.8E+14				
China EVA-2	91 ± 1	84	2.2E+14	1.1E+14				
China EVA-3	91 ± 1	>90	8.8E+13					
Europe EVA	91 ± 1	86						
Japan EVA-1	91 ± 1	94	1.1E+14	1.2E+14	9~12			
Japan EVA-2	91 ± 1	86	(deep texture)	3.4E+14	10~14			
NREL EVAs	91 ± 1	88	0.6~5.5E+14	0.2~1.4E+16	9~12			
US EVA-1	91 ± 1	88	0.8~1.1E+14	0.7~7.0E+14	9~10.5	20	88	7.02
						38	82	28.45
US PVB	91 ± 1	0	4.4E+12		Glass/Glass only	39	100	33.36
Japan PVB	91 ± 1	0	1.7E+12		Glass/Glass only	39	100	40.05
Europe PVB	91 ± 1	0	8.4E+12		Glass/Glass only			
US TPU	90 ± 2	0	6.4E+13					
US TPU	90 ± 2	0	7.3E+14					
Europe TPU	90 ± 2	0	1.1E+12					
TAT (Tedlar/Al/Tedlar)			4.31E+14			20	87	0.10
						85	100	0.83
TPT-primed			2.7~3.5E+15		~ 4 - 9 (to EVA)	20	84	0.89
					(EVA formulation dependent)	83	100	142.77
TPE Type			1.1~3.3E+16		> 12 (break up)	20	83	0.63
						85	100	94.39
Teonex Q65F (PEN)			5.5E+16			28	100	1.04
						85	100	35.24
Protekt HD			1.0E+17			40	100	3.20
						85	100	60.02

Encapsulation Process -- Double-Bag Vacuum Lamination (+ Oven)



High-performance vacuum laminator

- Use high-speed pump-down to ensure good vacuum before EVA is melted
- Ensure proper pressing of the module stack
- **Optimize temperature-pressure-time (T-P-t) profile that is materials, formulation, and system-dependent**

Process with EVA:

One-Step, One (Two)-Temp: Lamination and Curing in the laminator (**Fast-cure** EVA)

Two-Step, One (Two)-Temp: Lamination in laminator, Cure in Oven (**Slow-cure** EVA)

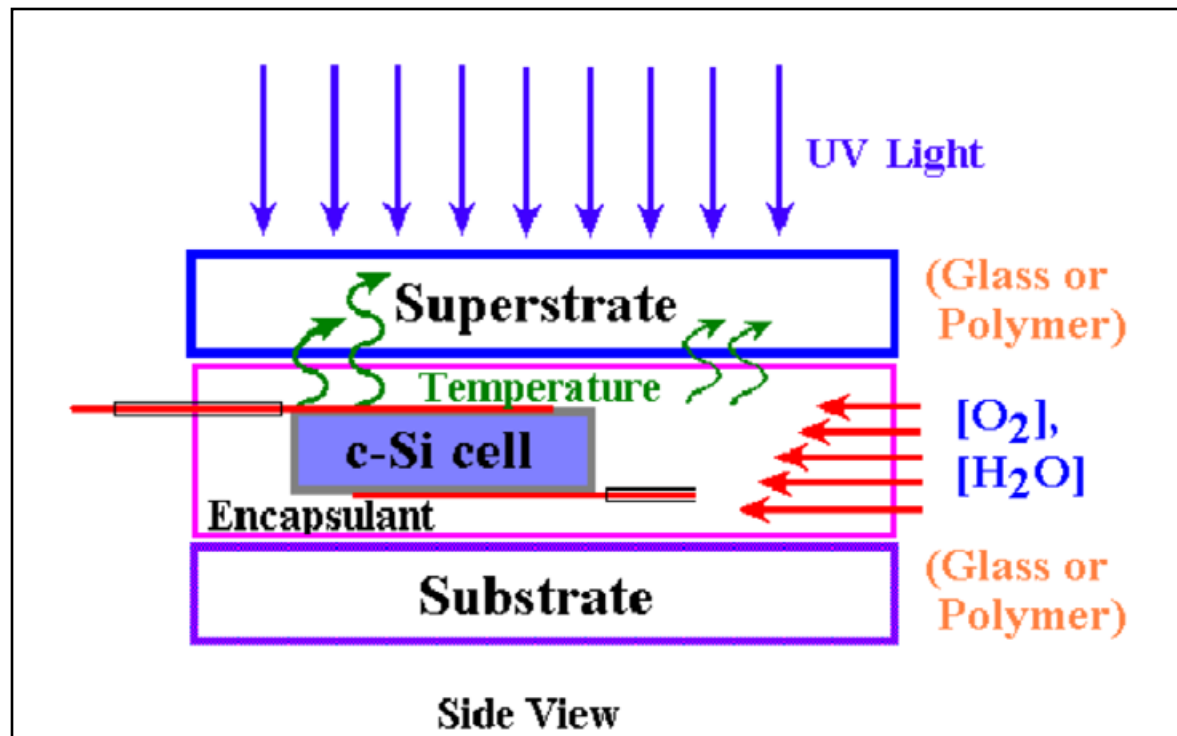
=> No Industry-wide Standard!

Typical Conditions for EVA:

- Lamination: 110° – 120°C for 4~10 min
- Curing at 140° – 150°C for ~6 to 30 min (depending on EVA formulation and process)
- **Gel ≥ 80%**

PVB and TPU: Roll-press possible and reworkable

Testing vs. Performance Reliability



Diurnal and Seasonal Temperature Variation;
Rain/Snow/Hail; Air pollutants

Potential Degradation: Optical,
Electrical, and/or Mechanical
(+ Delamination)

EVA Degradation: (Photo-discoloration vs. Photo-bleaching; O₂ diffusion limited; acetic acid generation);
Moisture Ingress: Delamination, corrosion, current leakage, T% loss

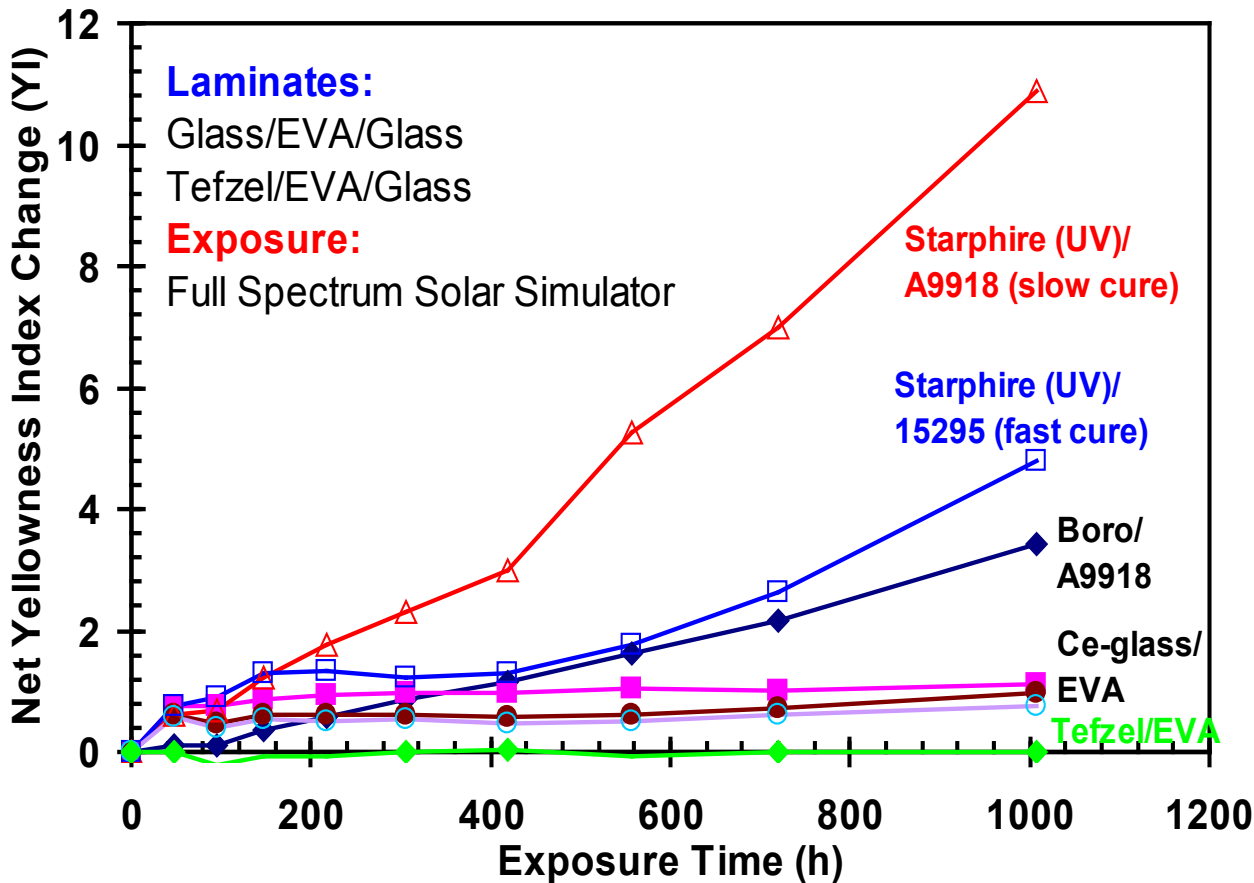
Equipment for Accelerated Exposure Tests: Solar simulators, Weatherometers, Damp Heat Chamber

Xe arc lamps for better simulation of solar spectrum



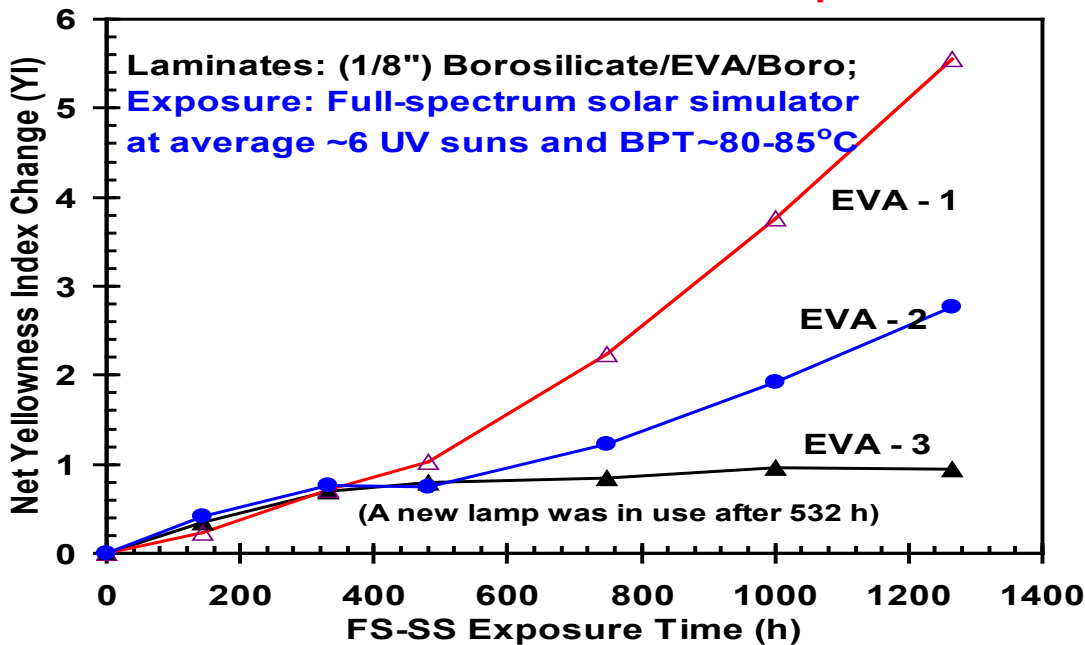
EVA Yellowing Rate is affected by Formulation, Processing, UV Filtering, and Air Permeability of Superstrate

Discoloration of EVA Laminated with Various Superstrates

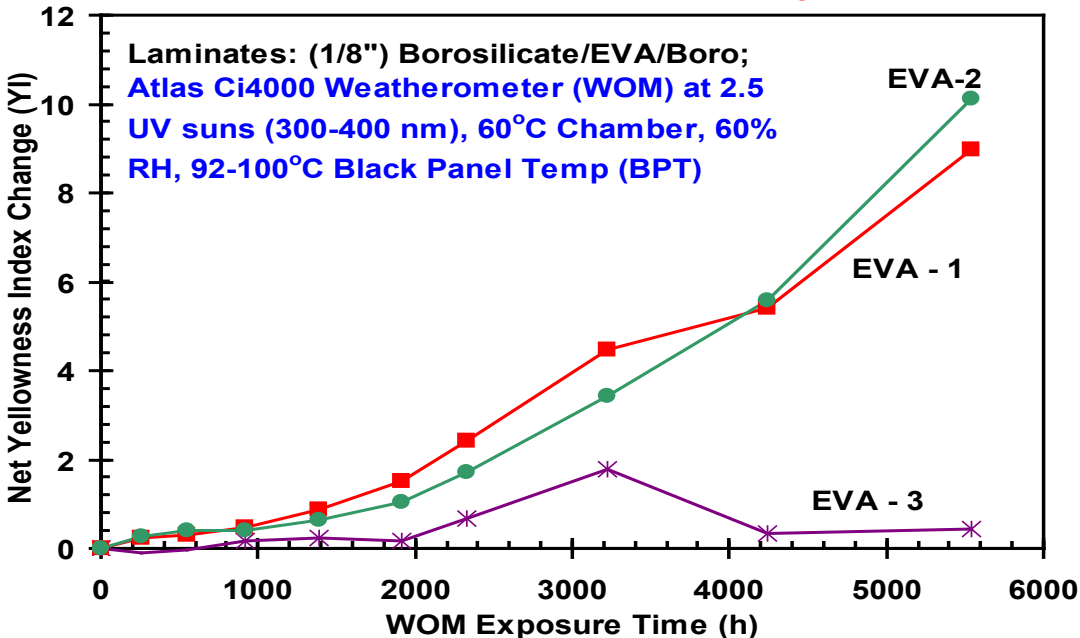


1. Slow-Cure > Fast Cure
2. UV-transmitting glass >> UV-filtering (Ce glass)
3. No yellowing with air-permeable Tefzel (photobleaching)
4. Competition between photo-discoloration (yellowing) and Photo-bleaching

Full Spectrum Solar Simulator Exposure



Atlas Ci4000 Weatherometer Exposure

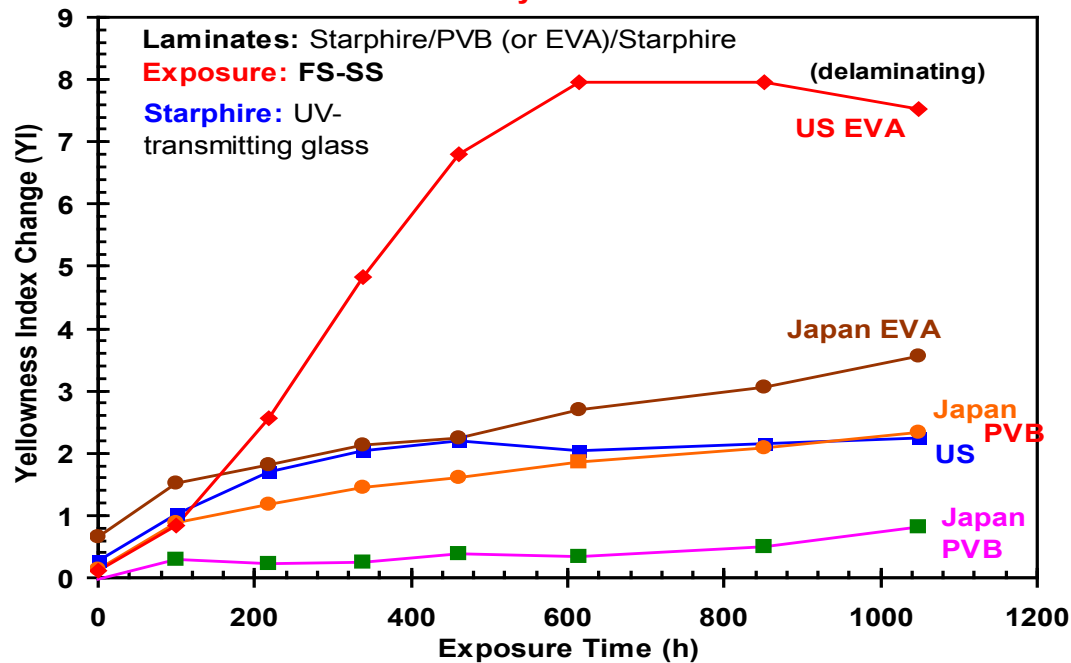


Accelerated Life Test (ALT) for Photothermal Stability of EVA

EVA Yellowing Rate is:

1. dependant on product formulation
 2. higher under solar simulator (~7 UV suns) than in weatherometer (2.5 UV suns)
 3. different in two test methods, but the trend remains unchanged
- => Shorter test time with greater light intensity

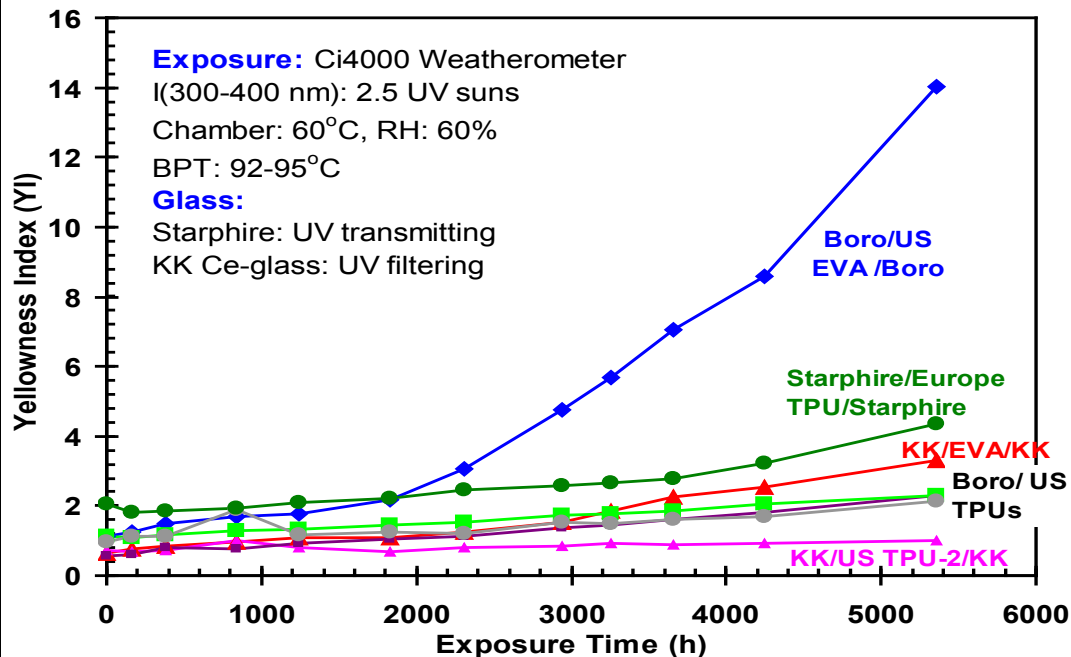
Photothermal Stability of PVB and EVA Laminates



Photothermal Stability ALT of PVB and TPU

1. Both PVB and TPU showed much less UV-induced yellowing than EVA
2. PVB can be used only on glass/glass laminates
3. Delamination of TPU from UV-transmitter glass can be serious depending on product quality
4. Adhesion of TPU to glass can be largely degraded by damp heat exposure

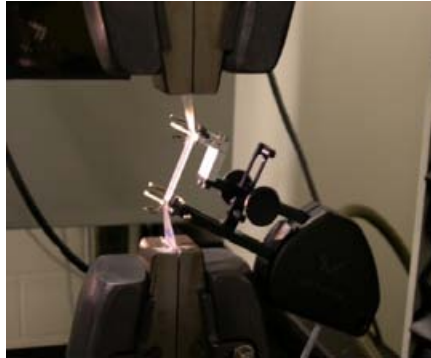
Discoloration of Glass/EVA or TPU/Glass Laminates



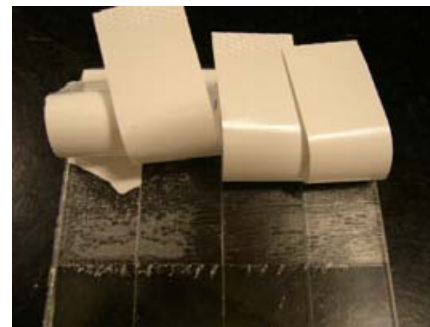
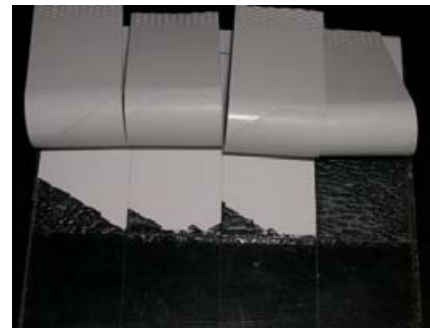
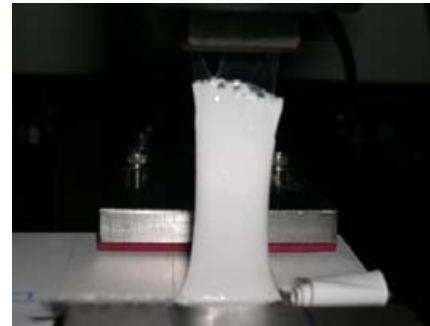
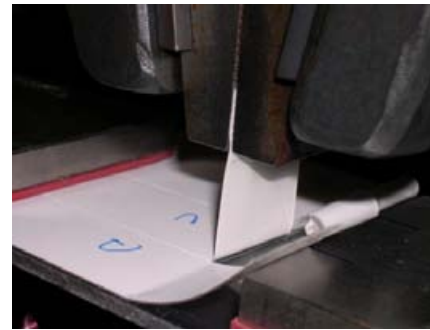
Mechanical Tests



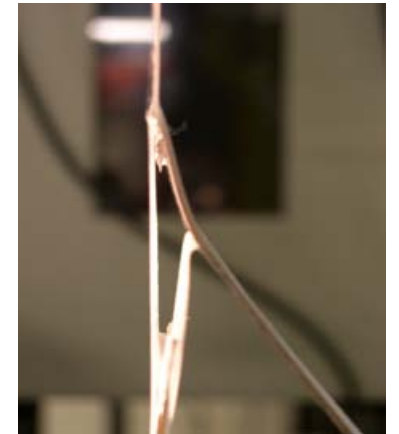
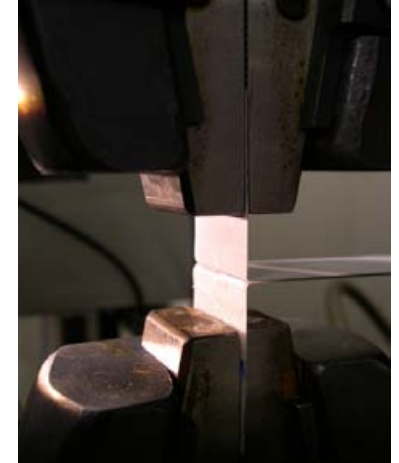
PC-controlled
Instron
Mechanical Tester



Tensile Test

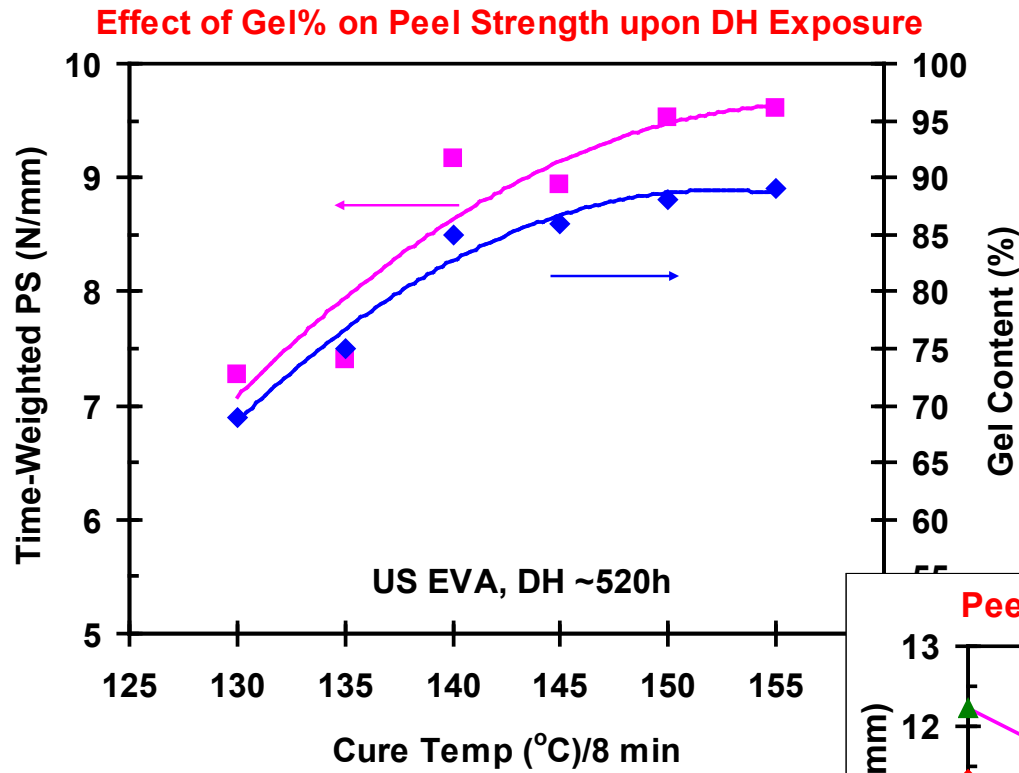


90° Peel Test

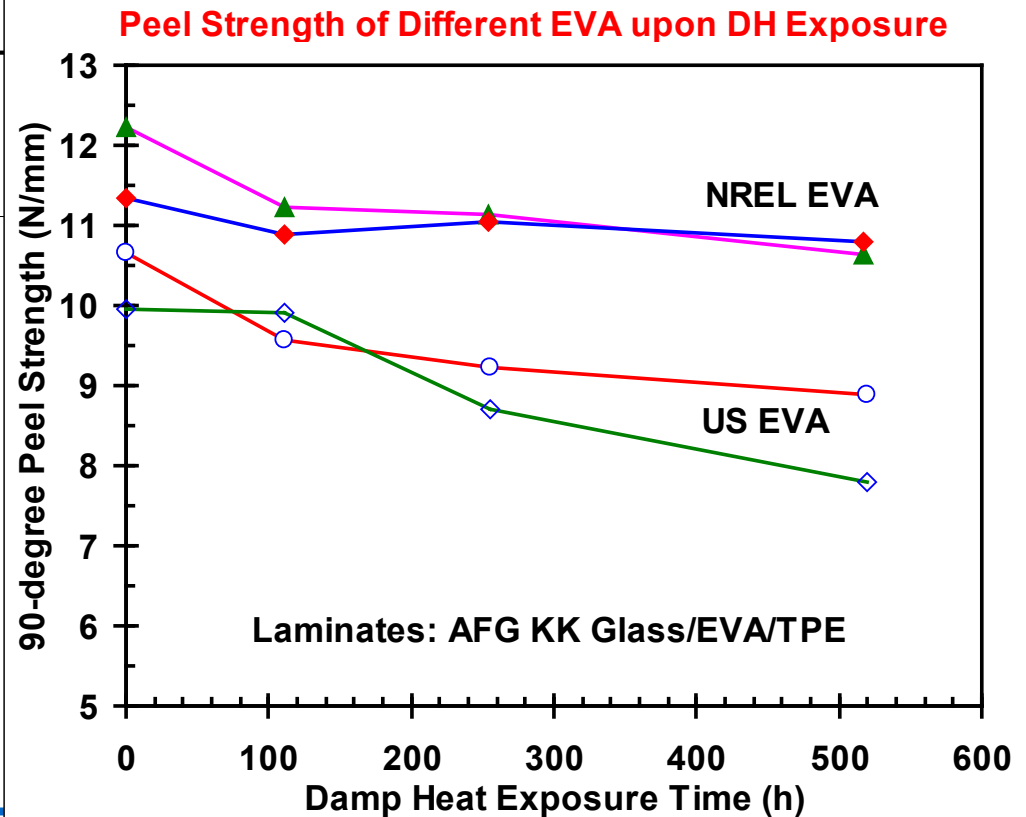


T-Peel Test

EVA Adhesion Strength affected by Processing Condition



and by Damp Heat Exposure Time

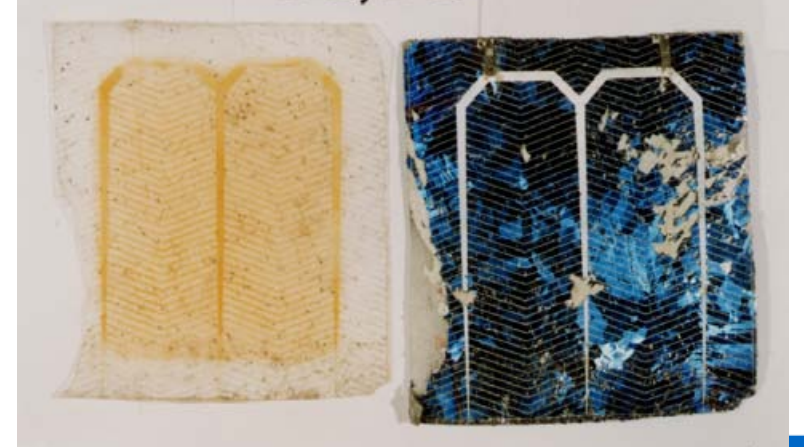
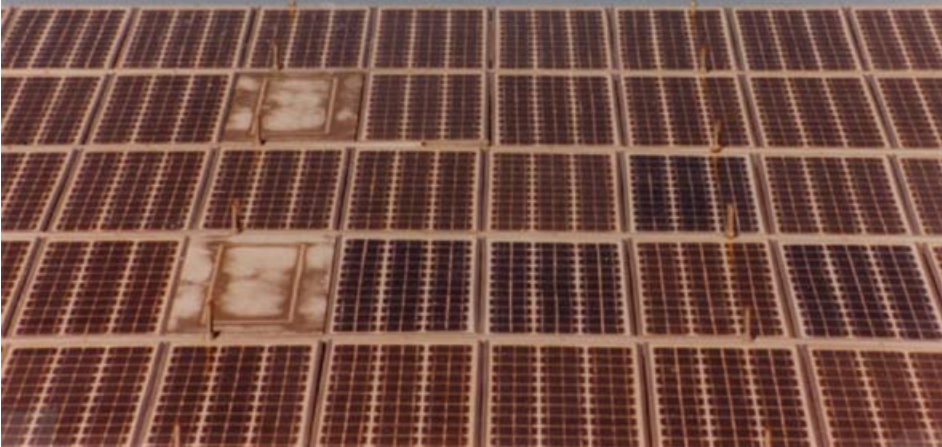


Some Photos of Field Modules

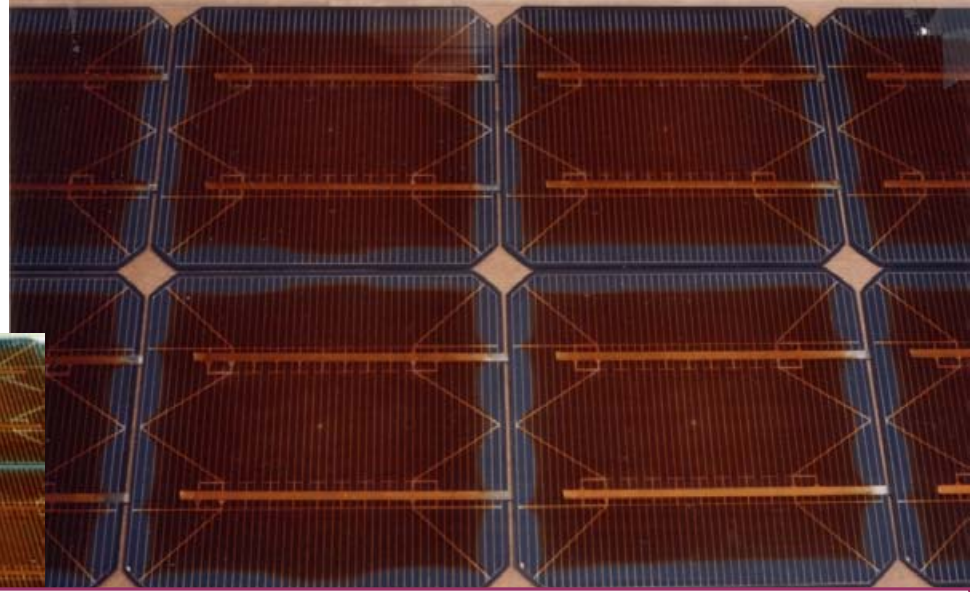
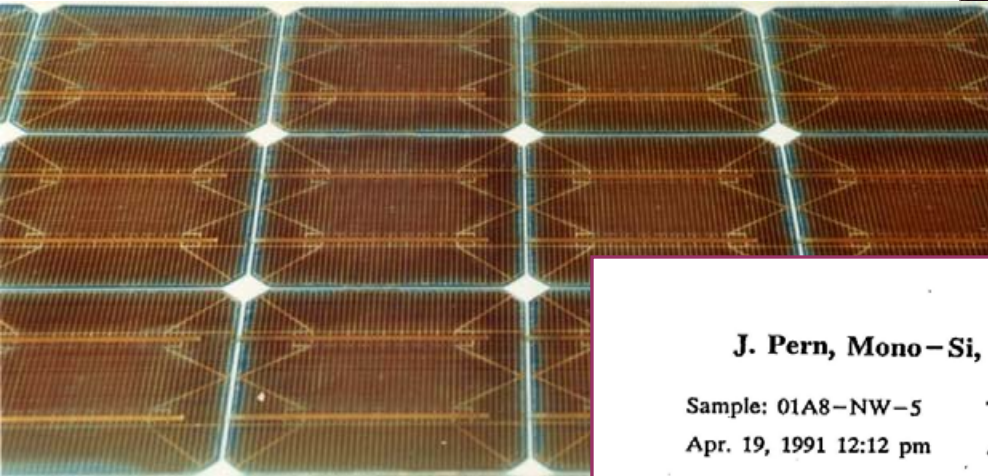
- Degraded by
 - Yellow-browning
 - Backsheet blistering & delamination
 - Corrosion by moisture ingress
 - Glass cracking by stress (glass/glass)
 - Other factors

EVA Browning in Field PV Modules

1990 EVA Browning Crisis: Severe EVA browning on mirror-enhanced PV arrays at Carrisa PV Power Plant, CA. Annual Power Output degraded by >45% from 1986-1990 (original: ~6 MW)



Large T% Loss and so Power Loss due to EVA Browning

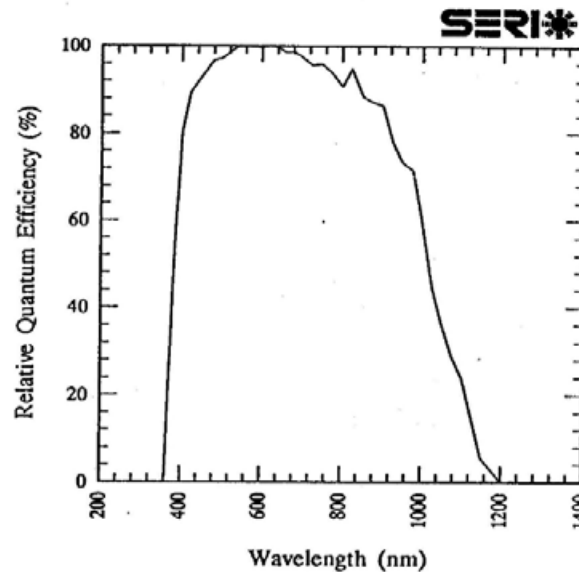


Virgin EVA

J. Pern, Mono-Si, encapsulated

Sample: 01A8-NW-5
Apr. 19, 1991 12:12 pm

Temperature = 25.0°C
Area used = 104.0 cm²

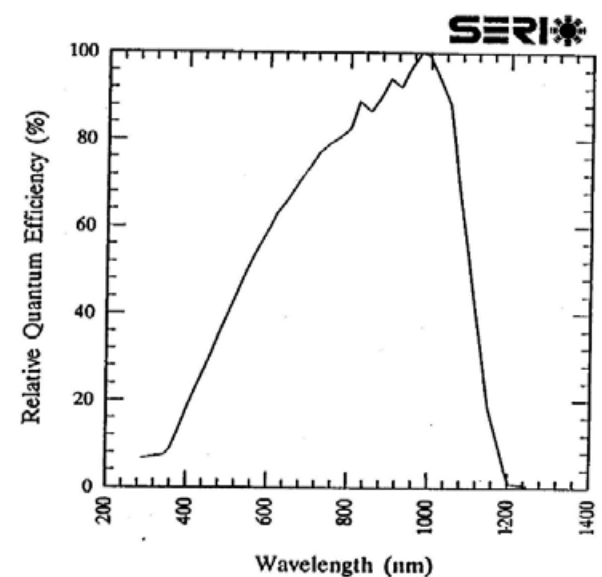


Dark Brown EVA

AS(R2,C5)

Sample: 4703-C-1
Mar. 7, 1991 1:31 pm

Temperature = 25.0°C
Area used = 0.967 cm²

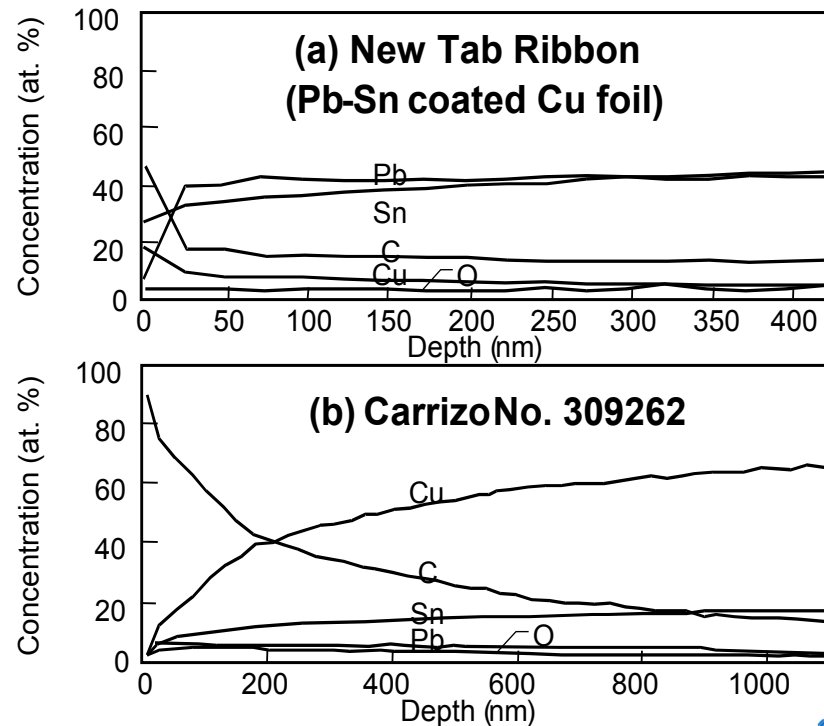


Corroded Pb-Sn Alloyed Cu Tab Ribbons by Acetic Acid from Browned EVA

EPMA Composition Analysis for the New and Exposed Tab Ribbons

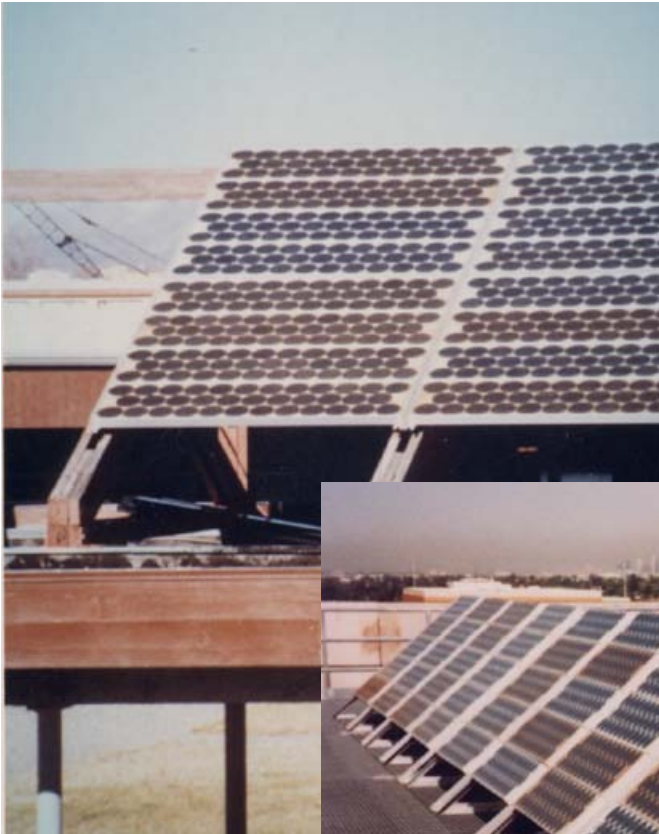
Sample Source PV Module No.	Solar Cell Location	Side of Tab Ribbon	EVA Color	Sn-L	Pb-M	Cu-L	O-K
New Tab				60.48	39.52		
Carrizo 1B	L9, R2	EVA	Light yellow	68.57	10.96	5.35	15.12
Carrizo 309259	L9, R2	EVA	Brown	5.80	41.13	13.27	39.80
Carrizo 309262	L9, R2	EVA	Dark brown	30.60	15.91	20.41	33.08
Carrizo 309262	L7, R3	EVA	Dark brown	4.62	46.56	8.08	40.74

Auger Depth Profile Analysis



P110-A048804

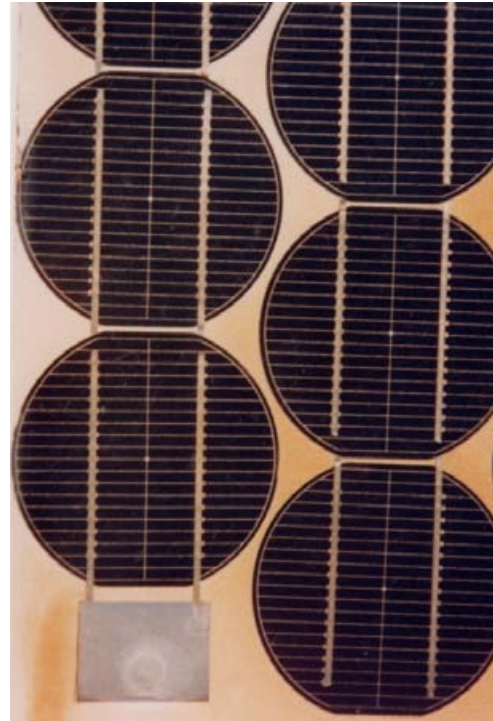
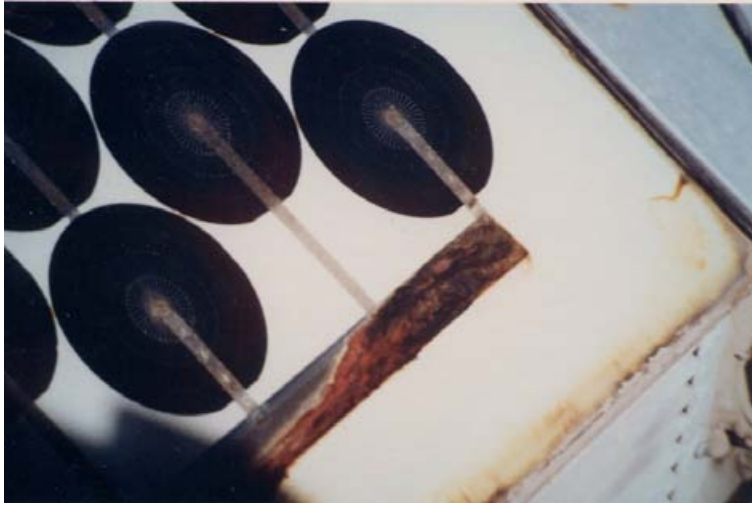
Irregular PVB Browning at ASU



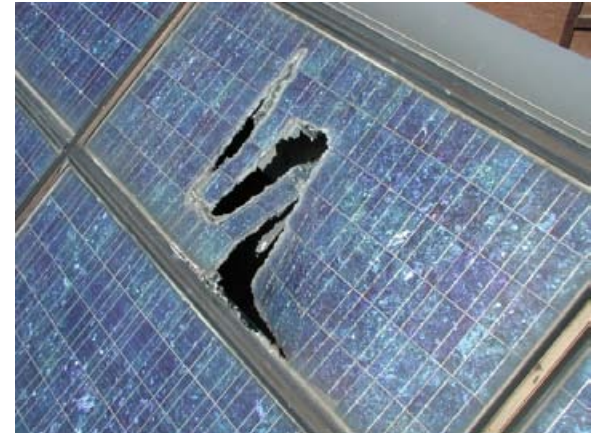
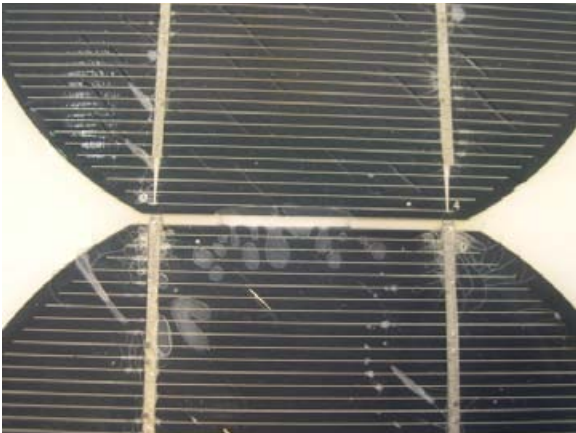
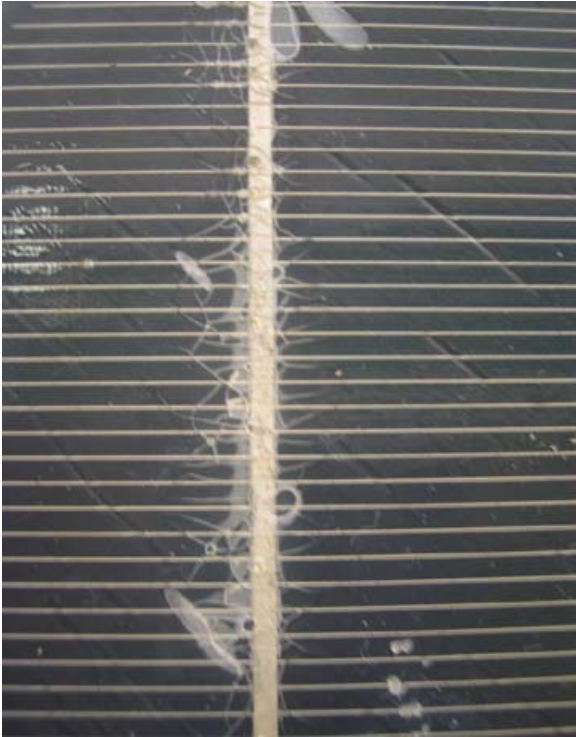
Blistering & Delamination of Backfoils



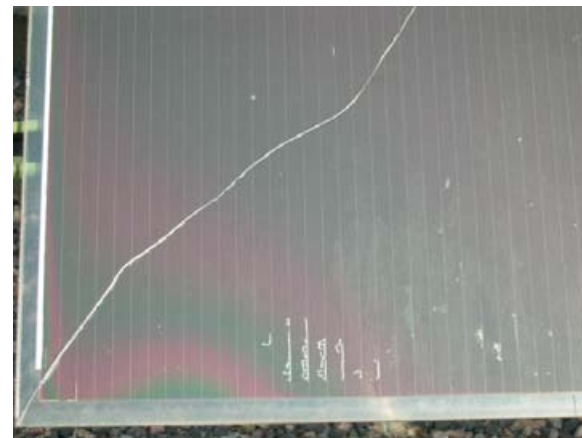
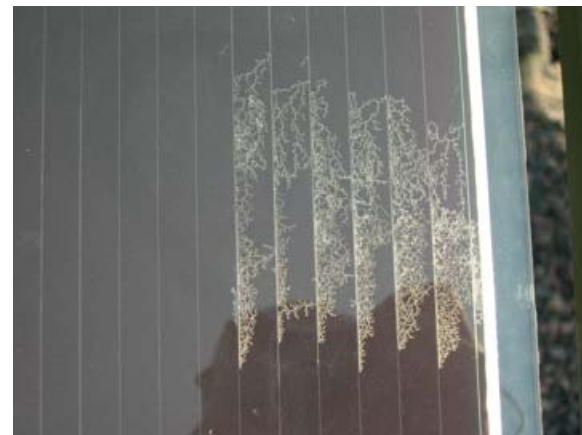
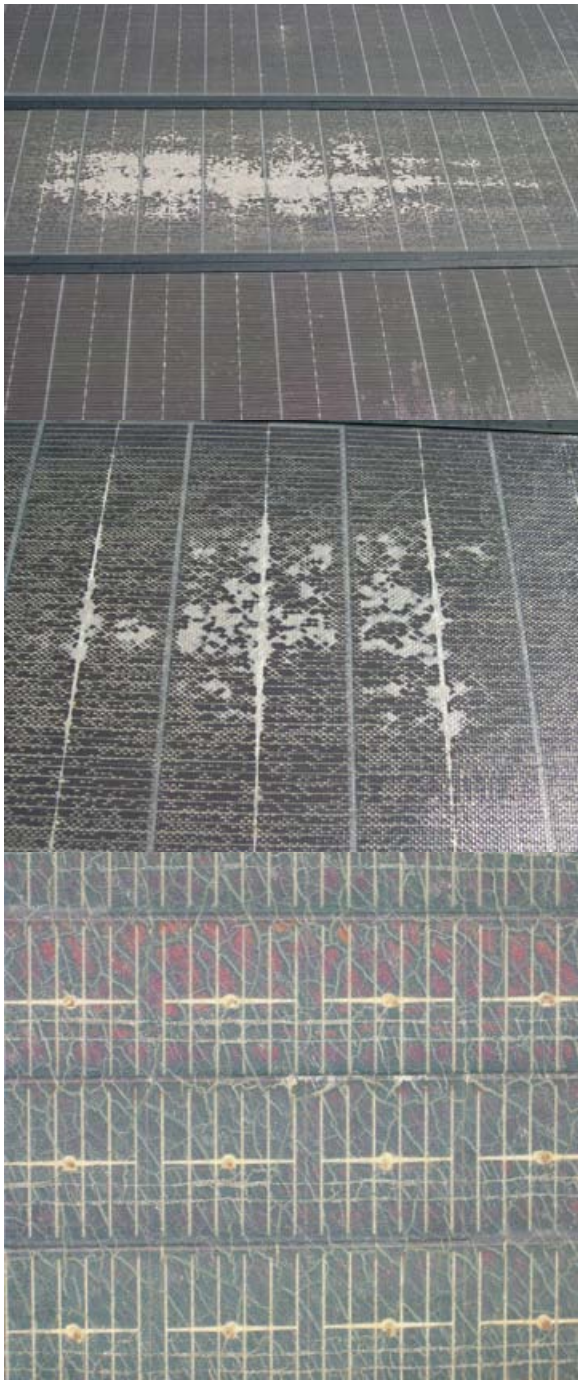
Water Ingress and Corrosion



More Degraded Modules



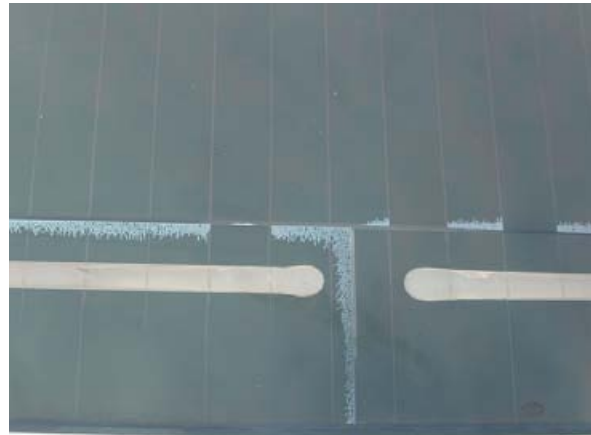
Thin Film Modules at NREL OTF



Field-Degraded Thin Film Modules



(photos: PowerLight)



Conclusions

- **Proper selection and initial tests of encapsulation materials are important.**
- **Different encapsulant formulations (e.g., EVA) give different quality and performance.**
- **Encapsulation method and processing conditions can affect the laminate quality and reliability of PV modules.**
- **Adequate accelerated exposure tests can be useful to assess the performance expectation of materials and quality of processed components.**
- **Overall module reliability is determined by all component materials and processing factors.**